



# Power MOSFETS

## DATASHEET

**LM1A092NAPFA**

N-Channel  
Enhancement Mode MOSFET

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Quality Management Systems  
ISO 9001:2015 Certificate

**N-Channel Enhancement Mode MOSFET****Pin Description**

TO-220F-3L <sub>(Top view)</sub>	Symbol	Symbol	Product Summary	
			N-Channel	Unit
		V <sub>DSS</sub>	100	V
		R <sub>DSON-Max</sub>	10.2	mΩ
		I <sub>D</sub>	47	A

**Feature**

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

**Applications**

- Power Management in DC/DC Converters
- USB Power Delivery (USB PD)

**Ordering Information**

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1A092NAPFA	TO-220F-3L	Tube	50 / Tube	1A092 □□□□□□

Note : □□□□□□ = Lot Code

**Absolute Maximum Ratings** (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V <sub>DSS</sub>	Drain-Source Voltage	100	V
V <sub>GSS</sub>	Gate-Source Voltage	±20	
T <sub>J</sub>	Maximum Junction Temperature	150	°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
I <sub>S</sub>	Diode Continuous Forward Current	T <sub>c</sub> =25°C 21	A
I <sub>DM</sub> <sup>①</sup>	Pulse Drain Current Tested	T <sub>c</sub> =25°C 118	A
I <sub>D</sub>	Continuous Drain Current	T <sub>c</sub> =25°C 47 T <sub>c</sub> =100°C 30	A
P <sub>D</sub>	Maximum Power Dissipation	T <sub>c</sub> =25°C 22.7 T <sub>c</sub> =100°C 9.1	W
I <sub>D</sub>	Continuous Drain Current	T <sub>A</sub> =25°C 13.7 T <sub>A</sub> =70°C 11	A
P <sub>D</sub>	Maximum Power Dissipation	T <sub>A</sub> =25°C 1.9 T <sub>A</sub> =70°C 1.2	W
I <sub>AS</sub> <sup>②</sup>	Avalanche Current, Single pulse	L=0.1mH 27 L=0.5mH 16	A
E <sub>AS</sub> <sup>②</sup>	Avalanche Energy, Single pulse	L=0.1mH 36 L=0.5mH 64	mJ

**Thermal Characteristics**

Symbol	Parameter	Rating	Unit
R <sub>θJC</sub>	Thermal Resistance-Junction to Case	Steady State	5.5 °C/W
R <sub>θJA</sub> <sup>③</sup>	Thermal Resistance-Junction to Ambient	Steady State	65 °C/W

Note ① : Max. current is limited by junction temperature

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

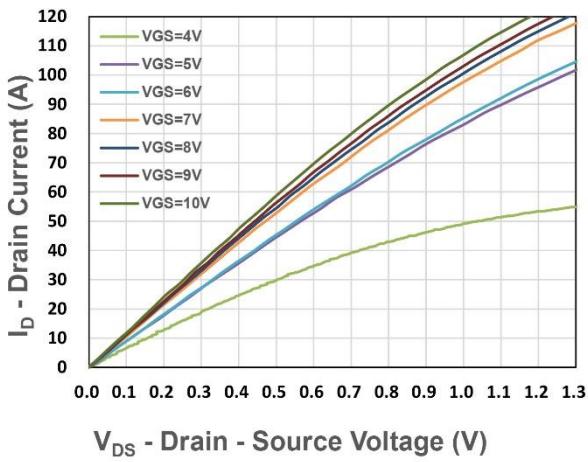
Note ③ : Surface Mounted on 1in<sup>2</sup> FR-4 board with 1oz

N-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$  Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
$\mathbf{BV_{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_{DS}=250\mu\text{A}$	100	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=80\text{V}, V_{GS}=0\text{V}$	-	-	1	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu\text{A}$	1.2	2	3	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	-	-	$\pm 100$	nA
$R_{DS(\text{ON})}^{\text{(4)}}$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}, I_{DS}=20\text{A}$	-	8.5	10.2	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_{DS}=20\text{A}$		12	15.6	
$g_{fs}$	Forward Transconductance	$V_{DS}=5\text{V}, I_{DS}=10\text{A}$	-	23	-	S
<b>Dynamic Characteristics <sup>(5)</sup></b>						
$R_G$	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V},$ Freq.=1MHz	-	1	-	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V},$ $V_{DS}=50\text{V},$ Freq.=1MHz	-	1928	-	pF
$C_{oss}$	Output Capacitance		-	504	-	
$C_{rss}$	Reverse Transfer Capacitance		-	35	-	
$t_{d(\text{ON})}$	Turn-on Delay Time	$V_{GS}=10\text{V}, V_{DS}=50\text{V},$ $I_D=1\text{A}, R_{GEN}=6\Omega$	-	9.1	-	nS
$t_r$	Turn-on Rise Time		-	17.5	-	
$t_{d(\text{OFF})}$	Turn-off Delay Time		-	32.1	-	
$t_f$	Turn-off Fall Time		-	73	-	
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=50\text{V}$ $I_D=20\text{A}$	-	22	-	nC
$Q_g$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=50\text{V},$ $I_D=20\text{A}$	-	41	-	
$Q_{gs}$	Gate-Source Charge		-	9.1	-	
$Q_{gd}$	Gate-Drain Charge		-	10.5	-	
<b>Source-Drain Characteristics</b>						
$V_{SD}^{\text{(4)}}$	Diode Forward Voltage	$I_{SD}=10\text{A}, V_{GS}=0\text{V}$	-	0.8	1.1	V
$t_{rr}$	Reverse Recovery Time	$I_F=10\text{A}, V_R=50\text{V}$	-	37.2	-	nS
$Q_{rr}$	Reverse Recovery Charge		-	34	-	nC

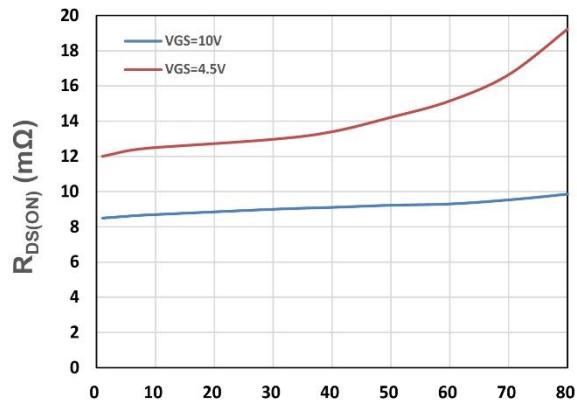
Note <sup>(4)</sup> : Pulse test (pulse width $\leq 300\text{us}$ , duty cycle $\leq 2\%$ ).Note <sup>(5)</sup> : Guaranteed by design, not subject to production testing.

## N-Channel Typical Characteristics



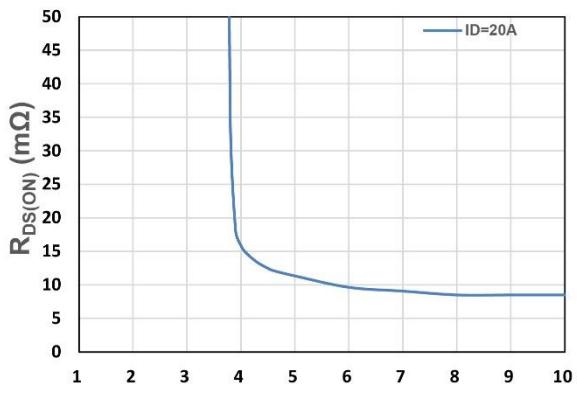
$I_D$  - Drain Current (A)  
 $V_{DS}$  - Drain - Source Voltage (V)

Figure 1. Output Characteristics

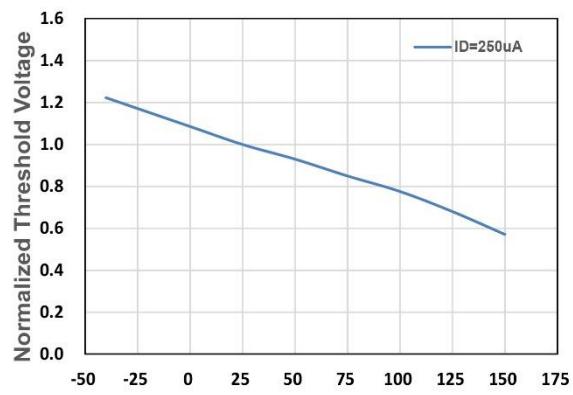


$I_D$  - Drain Current (A)

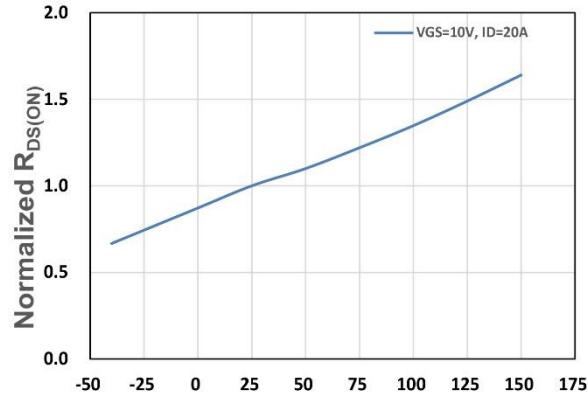
Figure 2. On-Resistance vs. ID



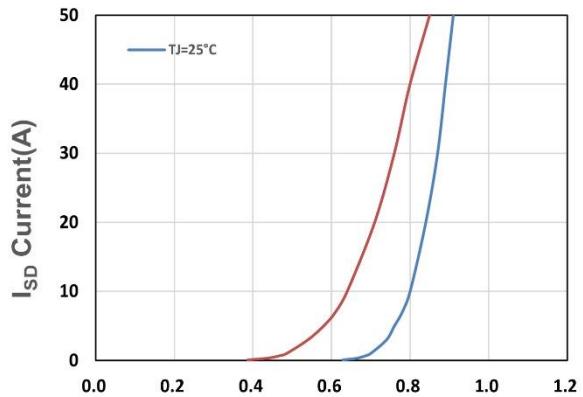
$V_{GS}$  - Gate - Source Voltage (V)  
Figure 3. On-Resistance vs. VGS



$T_j$ , Junction Temperature(°C)  
Figure 4. Gate Threshold Voltage

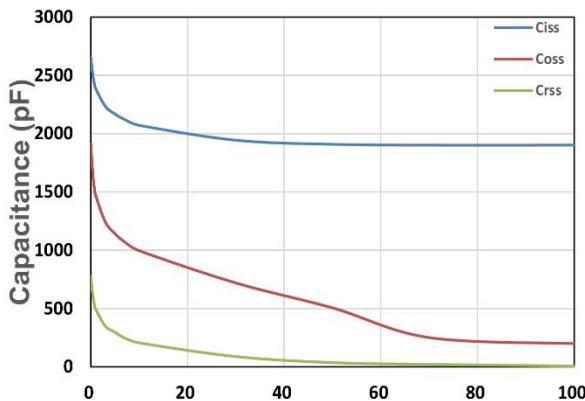


$T_j$  , Junction Temperature(°C)  
Figure 5. Drain-Source On Resistance

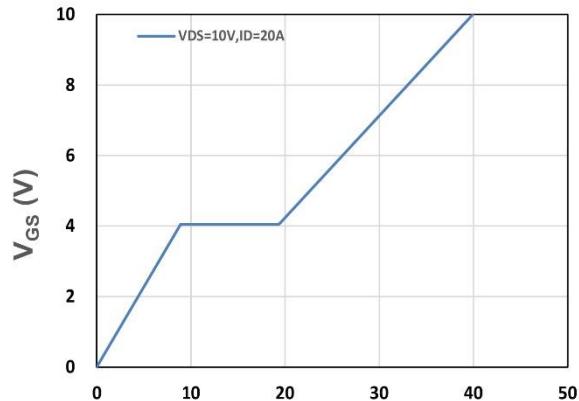


$V_{SD}$ , Source-Drain Voltage(V)  
Figure 6. Source-Drain Diode Forward

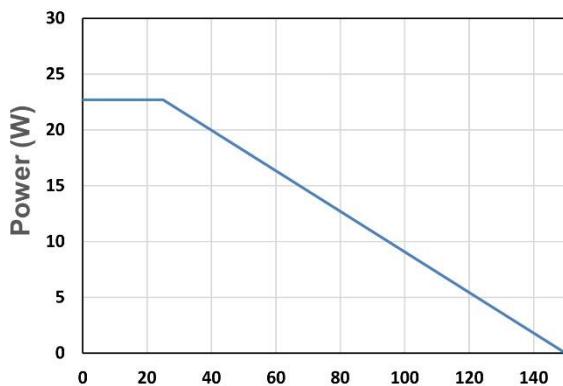
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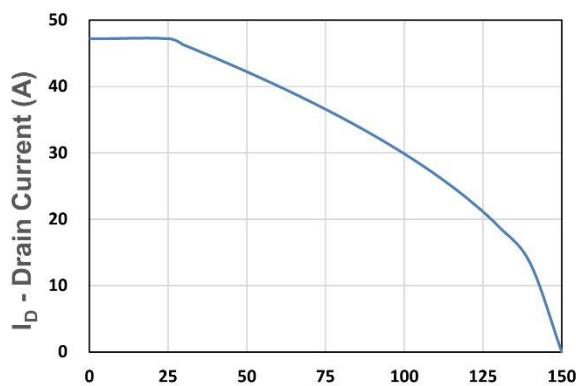
V<sub>DS</sub> - Drain - Source Voltage (V)  
Figure 7. Capacitance



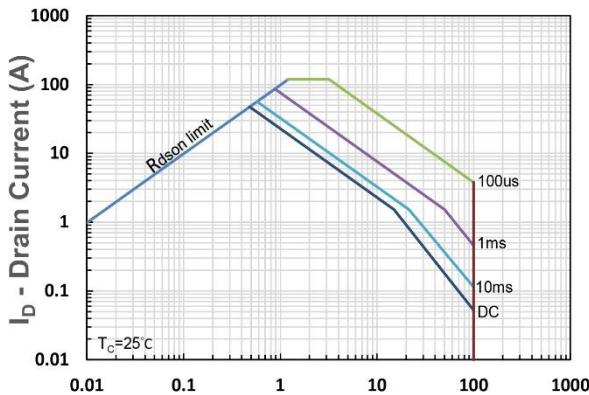
Q<sub>g</sub>, Total Gate Charge (nC)  
Figure 8. Gate Charge Characteristics



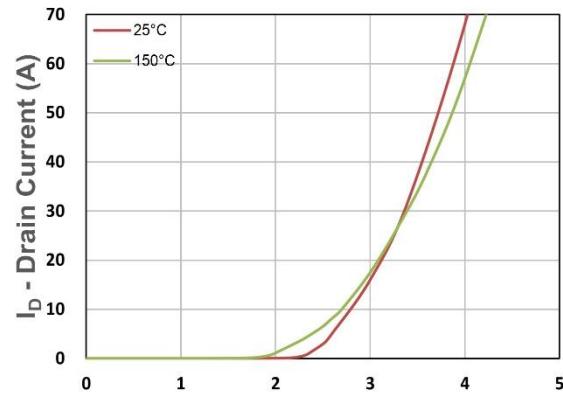
T<sub>c</sub> - Junction Temperature (°C)  
Figure 9. Power Dissipation



I<sub>D</sub> - Drain Current (A)  
Figure 10. Drain Current



I<sub>D</sub> - Drain Current (A)  
V<sub>DS</sub> - Drain-Source Voltage (V)  
Figure 11. Safe Operating Area



I<sub>D</sub> - Drain Current (A)  
V<sub>GS</sub> - Gate - Source Voltage (V)  
Figure 12. Transfer Characteristics

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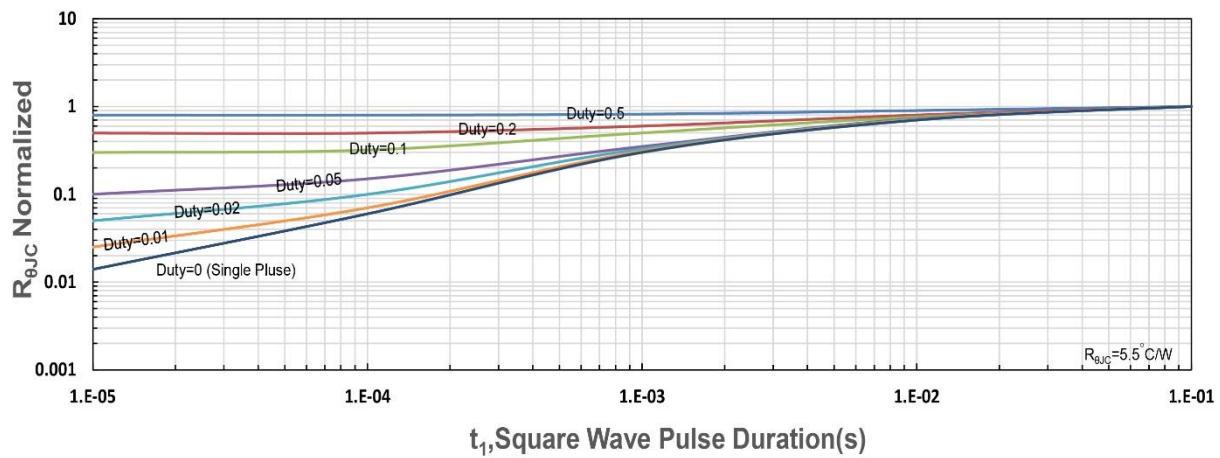


Figure 13.  $R_{\theta JC}$  Transient Thermal Impedance